MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet







SOT - 23

FEATURES

Switching Transistor

MARKING:2X

1. BASE

2. EMITTER

3. COLLECTOR

MAXIMUM RATINGS (T_a=25℃ unless otherwise noted)

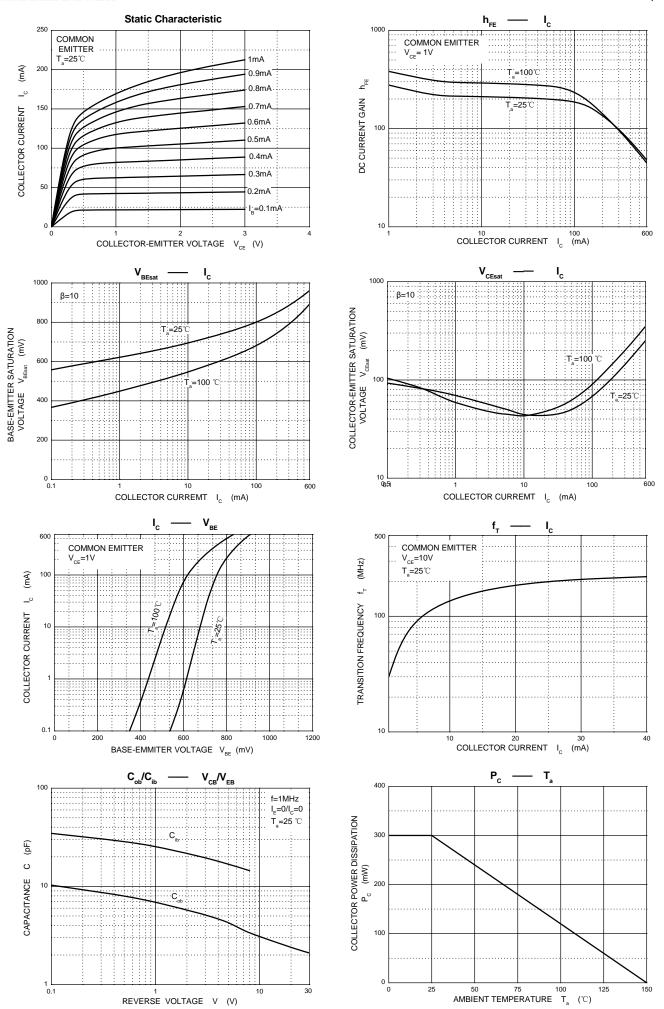
Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	60	V
V _{CEO}	Collector-Emitter Voltage	40	V
V _{EBO}	Emitter-Base Voltage	6	V
Ic	Collector Current	600	mA
Pc	Collector Power Dissipation	300	mW
R _{OJA}	Thermal Resistance From Junction To Ambient	417	°C/W
T _J ,T _{stg}	Operation Junction and Storage Temperature Range	-55~+150	℃

ELECTRICAL CHARACTERISTICS (T_a =25°C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =100 μ A,I _E =0	60			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =1mA,I _B =0	40			V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =100 μ A , I _C =0	6			V
Collector cut-off current	I _{CBO}	V _{CB} =50V,I _E =0			0.1	μА
Collector cut-off current	I _{CEX}	Vce=35V, Veb=0.4V			0.1	μА
Emitter cut-off current	I _{EBO}	V _{EB} =5V,I _C =0			0.1	μА
	h _{FE1}	V _{CE} =1V, I _C =0.1mA	20			
	h _{FE2}	V _{CE} =1V, I _C =1mA	40			
DC current gain	h _{FE3}	V _{CE} =1V, I _C =10mA	80			
	h _{FE4}	V _{CE} =1V, I _C =150mA	100		300	
	h _{FE5}	V _{CE} =2V, I _C =500mA	40			
Collector emitter esturation voltage	V _{CE(sat)}	I _C =150mA,I _B =15mA			0.4	V
Collector-emitter saturation voltage		I _C =500mA,I _B =50mA			0.75	V
Page emitter esturation voltage	V	I _C =150mA,I _B =15mA			0.95	V
Base-emitter saturation voltage	V _{BE(sat)}	I _C =500mA,I _B =50mA			1.2	V
Transition frequency	f⊤	V _{CE} =10V, I _C =20mA,f =100MHz	250			MHz
Delay time	t _d	Vcc=30V, VBE(off)=-2V			15	ns
Rise time	t _r	Ic=150mA , Iв1=15mA			20	ns
Storage time	t _s	Vcc=30V, Ic=150mA			225	ns
Fall time	t _f	I _{B1} =I _{B2} =15mA			60	ns



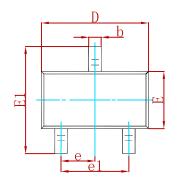


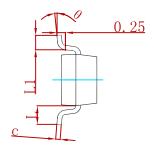


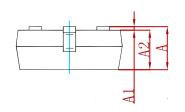




PACKAGE MECHANICAL DATA

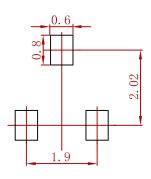






Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037 TYP		
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MMBT4401	SOT-23	3000



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